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Education

Ph.D.	Physics and Astronomy	University of California, Irvine	Jun. 2016
(Chemical and Materials Physics, Advisor: Prof. Eric O. Potma)			
M.S.	Physics and Astronomy	Seoul National University	Aug. 2007
B.S.	Physics	University of Seoul	Feb. 2005

Research Experiences

- 1. Mar. 2022 ~ Current: <u>Principal Research Scientist</u>, Hyperspectral Nano-imaging Lab, Korea Research Institute of Standards and Science, Daejeon, South Korea
- 2. Jun. 2020 ~ Feb. 2022: <u>Senior Research Scientist</u>, Hyperspectral Nano-imaging Lab, Korea Research Institute of Standards and Science, Daejeon, South Korea
- 3. Nov. 2016 ~ Nov. 2019: <u>Postdoctoral fellow</u> (Korea Research Fellow), Center for Nanocharacterization, Korea Research Institute of Standards and Science, Daejeon, South Korea
- 4. Feb. 2014 ~ Oct. 2016: <u>Research consultant</u>, Molecular Vista Inc., San Jose, USA
- 5. Aug. 2007 ~ Mar. 2009: Researcher, Park systems, Suwon, South Korea

Selected Academic honors

- 1. "OSK Rising Star 30" in Korea Optical Society 2020
- 2. "Best Post-doctor Award" in Korea Research Institute of Standards and Science 2019
- 3. "<u>Korea Research Fellowship 2016</u>" in Ministry of Science, ICT and Future Planning through the National Research Foundation of Korea
- 4. "Graduate Student Gold Award" in 2014 Material Research Society Fall meeting
- 5. "Best Poster Award in Symposium PP" in 2014 Material Research Society Fall meeting

News in public press

- 1. "Emerging a microscope that penetrates deep into semiconductor defects", YTN, 2018. 12. 11. (<u>https://www.ytn.co.kr/ ln/0115 201812110222574578</u>)
- 2. E. O. Potma, <u>J. Jahng</u> *et al.*, "Nanoscopic imaging with optical forces", *SPIE Newsroom*, (DOI: 10.1117/2.1201510.006171), 27 November (2015).

Selected Publications

- 1. AA Sifat, <u>J Jahng</u>, EO Potma, "Photo-induced force microscopy (PiFM)–principles and implementations", *Chem. Soc. Rev.*, **51**, 4208–4222 (2022).
- 2. <u>J. Jahng</u> et al., "Nanoscale spectroscopic origins of photoinduced tip-sample force in the midinfrared: dipole and thermal", *Proc. Natl. Acad. Sci.*, **116** (52), 26359-26366 (2019).
- 3. <u>J. Jahng</u> et al., "Linear and nonlinear optical spectroscopy at the nanoscale with photo-induced force microscopy", *Acc. Chem. Res.* **48** (10), 2671-2679 (2015)